


About IEEE | IEEE Memberships | IEEE Spectrum | Products and Services | Conferences | IEEE Organizations | IEEE Home

 **IEEE Xplore™**

Help FAQ Terms Release Notes Release

Welcome to IEEE Xplore™

- ☐ Home
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account

 Print Format

Your search matched **215** of **720981** documents.
Results are shown **50** to a page, sorted by **publication year** in **descending** order.
You may refine your search by editing the current search expression or entering a new one the te
Then click **Search Again**.

(insulating <or> dielectric) <and> (fluoride <or> fluorocarbon)

Search Again

Results:

Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD**

201 **The poling of multiple-layer polyvinylidene fluoride films and the piezoelectricities**

Wang Shengjun; Zhao Yanxia; Yan Fuming

Electrets, 1988. (ISE 6) Proceedings., 6th International Symposium on (IEEE No.88CH2593-2) , 1988

Page(s): 598 -602

[\[Abstract\]](#) [\[PDF Full-Text \(156 KB\)\]](#) **CNF**

202 **AC poling of solution cast films of polyvinylidene fluoride/lead zirconate composites**

Sinham, D.; Pillai, P.K.C.

Electrets, 1988. (ISE 6) Proceedings., 6th International Symposium on (IEEE No.88CH2593-2) , 1988

Page(s): 525

[\[Abstract\]](#) [\[PDF Full-Text \(16 KB\)\]](#) **CNF**

203 **Constant current corona triode with bias grid voltage control**

Giacometti, J.A.; Campos, J.S.

Electrets, 1988. (ISE 6) Proceedings., 6th International Symposium on (IEEE No.88CH2593-2) , 1988

Page(s): 404 -408

[\[Abstract\]](#) [\[PDF Full-Text \(156 KB\)\]](#) **CNF**

204 **Piezo- and pyroelectricity and structure of doped polymers**

Danz, R.; Elling, B.; Kuentler, W.; Pinnow, M.; Schmolke, R.; Wedel, A.; Ge

Electrets, 1988. (ISE 6) Proceedings., 6th International Symposium on (IEEE No.88CH2593-2) , 1988

Page(s): 199 -203

[About IEEE](#) | [IEEE Memberships](#) | [IEEE Spectrum](#) | [Products and Services](#) | [Conferences](#) | [IEEE Organizations](#) | [IEEE Home](#)**IEEE** Xplore™

Search

[Help](#) [FAQ](#) [Terms](#) [Release Notes](#)[Release](#)

Welcome to IEEE Xplore™

- ☐ Home
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account

Print Format

Your search matched **215** of **720981** documents.Results are shown **50** to a page, sorted by **publication year** in **descending** order.

You may refine your search by editing the current search expression or entering a new one the te

Then click **Search Again**.**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 TRG-OES measurements of electron temperatures during fluor car plasma etching of SiO/sub 2/ damage test wafers**

Schabel, M.J.; Donnelly, V.M.; Cheung, K.P.; Kornblit, A.; Layadi, N.; Tai, W
Plasma- and Process-Induced Damage, 2001 6th International Symposium o
Page(s): 60 -63

[\[Abstract\]](#) [\[PDF Full-Text \(288 KB\)\]](#) **CNF****2 Enhanced self aligned contact (SAC) etch stop window by using C/ 4/F/sub 6/ chemistry**

Wang, J.; Pu, B.; Bjokman, C.; Komatsu, T.; Woo, J.W.; Ruiping Wang; Hon Shan

Advanced Semiconductor Manufacturing Conference, 2001 IEEE/SEMI , 2001
Page(s): 101 -105

[\[Abstract\]](#) [\[PDF Full-Text \(576 KB\)\]](#) **CNF****3 Pyroelectric activity of ferroelectric PT/PVDF-TRFE**

Ploss, B.; Ploss, B.; Shin, F.G.; Chan, H.L.W.; Choy, C.L.

Dielectrics and Electrical Insulation, IEEE Transactions on [see also Electrica
Insulation, IEEE Transactions on] , Volume: 7 Issue: 4 , Aug. 2000

Page(s): 517 -522

[\[Abstract\]](#) [\[PDF Full-Text \(504 KB\)\]](#) **JNL****4 Dielectric permittivity of PCLT/PVDF-TRFE nanocomposites**

Chan, H.L.W.; Zhang, Q.Q.; Ng, W.Y.; Choy, C.L.

Dielectrics and Electrical Insulation, IEEE Transactions on [see also Electrica
Insulation, IEEE Transactions on] , Volume: 7 Issue: 2 , April 2000

Page(s): 204 -207